


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527789	<b>Applicant(s)/Patent Under Reexamination</b>  AIKELE ET AL.
	<b>Examiner</b>  Kin-Chan Chen	<b>Art Unit</b>  1792

SEARCHED			
Class	Subclass	Date	Examiner
438	700, 702, 706, 719, 723, 724	6/5/2009	KCC
216	67, 74, 79	6/5/2009	KCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST KEY-WORD SEARCH, USPAT, EPO, JPO, USPG_PUB, DERWENT, IBM_TDB, INVENTOR SEARCH	6/5/2009	KCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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